

**Search Notes**

Application/Control No.

10/791,815

Examiner

David Buttner

Applicant(s)/Patent under  
Reexamination

FUJISAWA ET AL.

Art Unit

1712

**SEARCHED**

| Class | Subclass | Date | Examiner |
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**INTERFERENCE SEARCHED**

| Class | Subclass | Date      | Examiner |
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| 524   | all      | 5/24/2006 | DB       |
| 473   | all      | 5/24/2006 | DB       |
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**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

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